

CET

CEP740G/CEB740G □ CEF740G

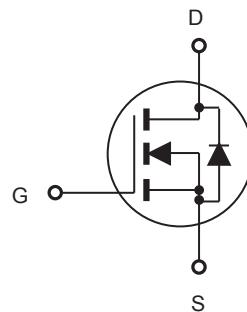
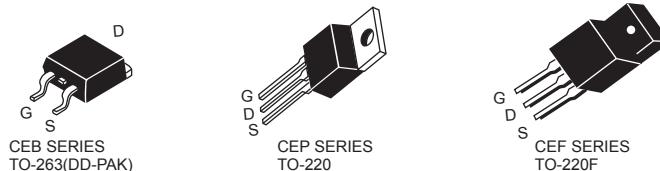
N-Channel Enhancement Mode Field Effect Transistor

PRELIMINARY

FEATURES

Type	V_{DSS}	$R_{DS(ON)}$	I_D	@ V_{GS}
CEP740G	400V	0.55Ω	10A	10V
CEB740G	400V	0.55Ω	10A	10V
CEF740G	400V	0.55Ω	10A ^e	10V

- Super high dense cell design for extremely low $R_{DS(ON)}$.
- High power and current handing capability.
- Lead free product is acquired.



ABSOLUTE MAXIMUM RATINGS

 $T_C = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Limit		Units
		TO-220/263	TO-220F	
Drain-Source Voltage	V_{DS}	400		V
Gate-Source Voltage	V_{GS}	± 30		V
Drain Current-Continuous	I_D	10	10 ^e	A
Drain Current-Pulsed ^a	I_{DM}^f	40	40 ^e	A
Maximum Power Dissipation @ $T_C = 25^\circ\text{C}$ - Derate above 25°C	P_D	125 1.0	40 0.32	W W/ $^\circ\text{C}$
Operating and Store Temperature Range	T_J, T_{stg}	-55 to 150		$^\circ\text{C}$

Thermal Characteristics

Parameter	Symbol	Limit		Units
Thermal Resistance, Junction-to-Case	R_{JC}	1.0	3.1	$^\circ\text{C}/\text{W}$
Thermal Resistance, Junction-to-Ambient	R_{JA}	62.5	65	$^\circ\text{C}/\text{W}$

This is preliminary information on a new product in development now .
Details are subject to change without notice .

Rev 1. 2007.Nov.
<http://www.cetsemi.com>



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Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	400			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = 400\text{V}, V_{\text{GS}} = 0\text{V}$		50		μA
Gate Body Leakage Current, Forward	I_{GSSF}	$V_{\text{GS}} = 30\text{V}, V_{\text{DS}} = 0\text{V}$		100		nA
Gate Body Leakage Current, Reverse	I_{GSSR}	$V_{\text{GS}} = -30\text{V}, V_{\text{DS}} = 0\text{V}$		-100		nA
On Characteristics^b						
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{GS}} = V_{\text{DS}}, I_D = 250\mu\text{A}$	2		4	V
Static Drain-Source On-Resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}} = 10\text{V}, I_D = 6\text{A}$		450	550	$\text{m}\Omega$
Forward Transconductance	g_{FS}	$V_{\text{DS}} = 50\text{V}, I_D = 6\text{A}$		6		S
Dynamic Characteristics^c						
Input Capacitance	C_{iss}	$V_{\text{DS}} = 25\text{V}, V_{\text{GS}} = 0\text{V}, f = 1.0 \text{ MHz}$		1245		pF
Output Capacitance	C_{oss}			190		pF
Reverse Transfer Capacitance	C_{rss}			25		pF
Switching Characteristics^c						
Turn-On Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = 200\text{V}, I_D = 10\text{A}, V_{\text{GS}} = 10\text{V}, R_{\text{GEN}} = 9.1\Omega$		20	40	ns
Turn-On Rise Time	t_r			9	18	ns
Turn-Off Delay Time	$t_{\text{d}(\text{off})}$			50	100	ns
Turn-Off Fall Time	t_f			8	16	ns
Total Gate Charge	Q_g	$V_{\text{DS}} = 320\text{V}, I_D = 10\text{A}, V_{\text{GS}} = 10\text{V}$		35.6	47.3	nC
Gate-Source Charge	Q_{gs}			6.7		nC
Gate-Drain Charge	Q_{gd}			12		nC
Drain-Source Diode Characteristics and Maximum Ratings						
Drain-Source Diode Forward Current	I_S^f				10	A
Drain-Source Diode Forward Voltage ^b	V_{SD}	$V_{\text{GS}} = 0\text{V}, I_S = 10\text{A}$			2	V

Notes :

a.Repetitive Rating : Pulse width limited by maximum junction temperature .

b.Pulse Test : Pulse Width $\leq 300\mu\text{s}$. Duty Cycle $\leq 2\%$.□

c.Guaranteed by design, not subject to production testing.□

d.Limited only by maximum temperature allowed .

e.Pulse width limited by safe operating area .

f.Full package $I_{\text{S}(\text{max})} = 5.5\text{A}$.

CEP

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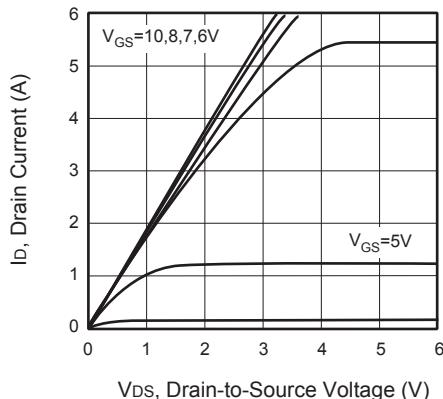


Figure 1. Output Characteristics

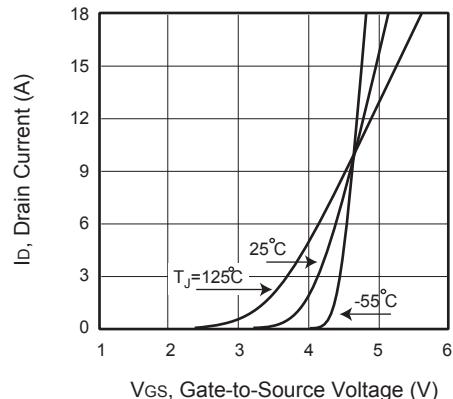


Figure 2. Transfer Characteristics

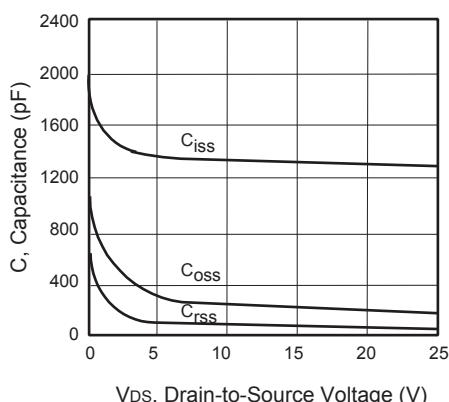


Figure 3. Capacitance

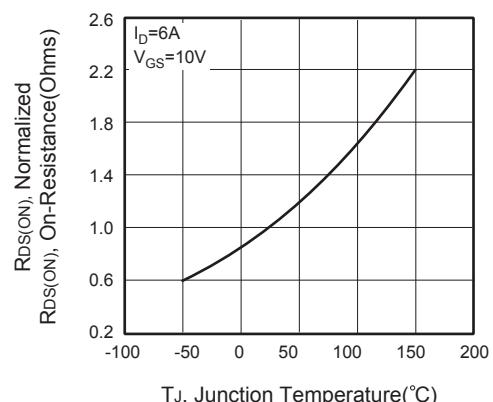


Figure 4. On-Resistance Variation with Temperature

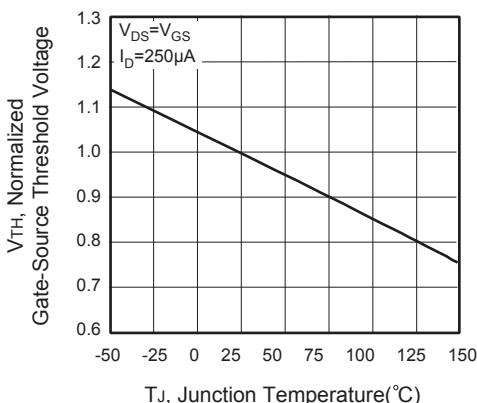


Figure 5. Gate Threshold Variation with Temperature

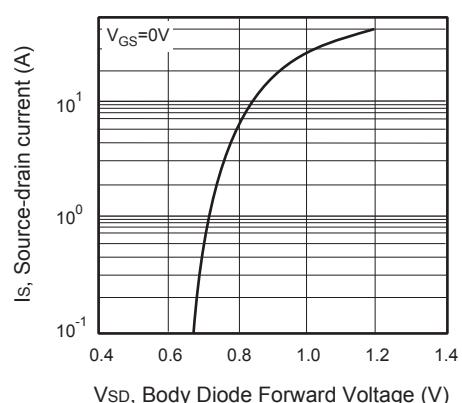


Figure 6. Body Diode Forward Voltage Variation with Source Current

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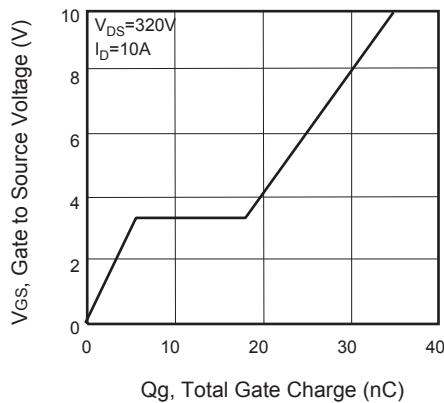


Figure 7. Gate Charge

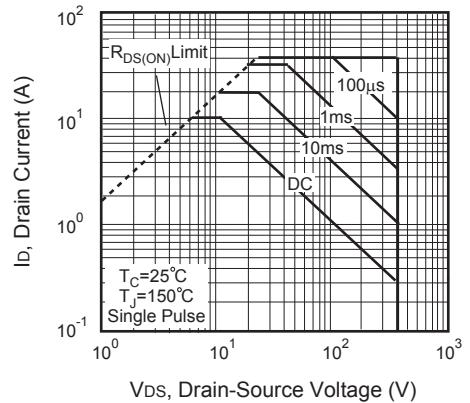


Figure 8. Maximum Safe Operating Area

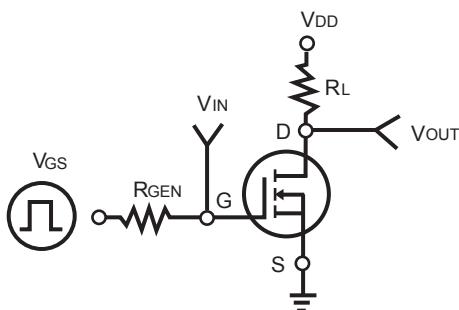


Figure 9. Switching Test Circuit

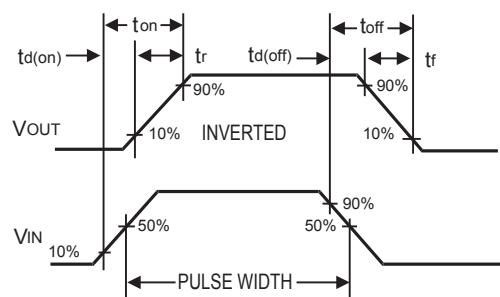


Figure 10. Switching Waveforms

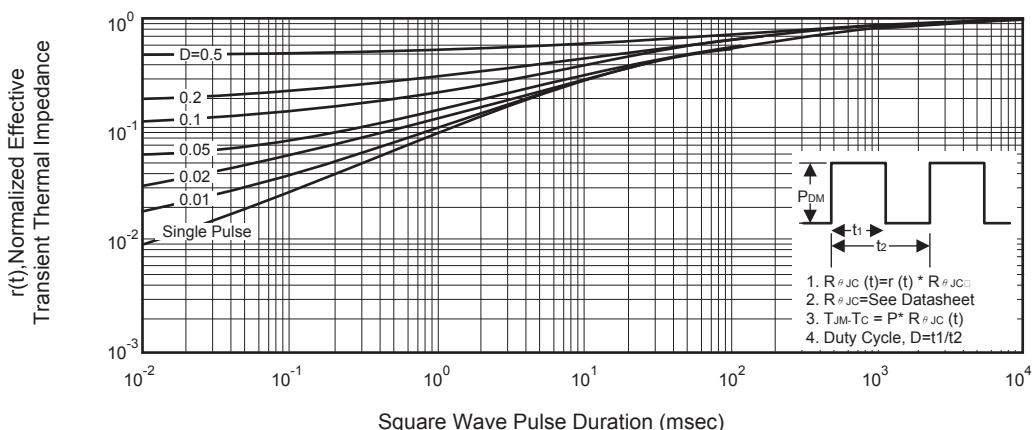


Figure 11. Normalized Thermal Transient Impedance Curve